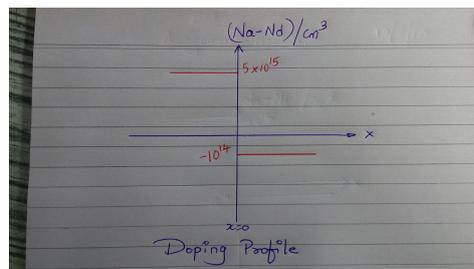


D. J. SANGHVI COLLEGE OF ENGINEERING
DEPARTMENT OF ELECTRONICS ENGINEERING
ELECTRONIC DEVICES SEM III
Homework Assignment 01

N.B. :

[Total Marks: 60]

- 1) Write your **SAP ID** on the top of the first page.
 - 2) This assignment is based on **PN junction and BJT** topic.
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1. For a Si pn junction at $T=300K$, acceptor dopants and donor dopant have equal concentration of $10^{17}/cm^3$, $D_n = 25cm^2/s$, $D_p = 15cm^2/s$, $\tau_p = \tau_n = 50ns$, Area $=10^{-4}/cm^2$. Find the value of forward current for the forward-bias of $0.7V$. **[15]**
 2. Breakdown voltage of a zener diode is decided by ----- **[02]**
 3. Justify how Eber-moll model works for all operating modes of BJT ? **[08]**
 4. An abrupt Si pn junction has $N_A = 10^{17}/cm^3$ on p-side and $N_D = 10^{16}/cm^3$ on n-side at $300K$. **[10]**
 - a) Draw an equilibrium energy-band diagram and calculate position's of fermi level on each side.
 - b) Calculate V_{bi} from the energy-band diagram in a).
 - c) Compare the results from a) with V_{bi} calculated from its formula.
 5. A Si pn junction has $V_{bi} = 0.65V$ and acceptor concentration on p-side is 100 times greater than donor concentration on n-side. Find the width of depletion region and value of depletion capacitance per unit area when a reverse bias voltage of $10V$ is applied across it. **[10]**
 6. Justify why the space charge width increases with reverse-bias voltage in a pn junction diode ? **[05]**
 7. A Si pn junction at $T=300K$ has doping profile shown below: Estimate the following: **[10]**
 - i) Built-in potential
 - ii) x_n and x_p at zero bias
 - iii) Sketch E-field Vs distance for the given situation.



Parameter	Emitter	Base	Collector
Dopant concentration (cm^{-3})	10^{18} (n-type)	10^{17} (n-type)	10^{15} (n-type)
Width (μm)	0.5	0.5	2
Minority-carrier lifetime (s)	10^{-7}	10^{-6}	10^{-5}

8. Consider a Si npn BJT with emitter area $A = 10^{-7} cm^2$, maintained at room temperature ($T = 300K$), with parameters for each of the regions as shown in the table above: [EC 40]

Various current components in base, emitter and collector are:

$$I_{Ep} = qA \frac{D_E}{L_E} p_{E0} \frac{\cosh(W'_E/L_E)}{\sinh(W'_E/L_E)} (e^{V_{BE}/V_t} - 1)$$

$$I_{Cp} = -qA \frac{D_C}{L_C} p_{C0} \frac{\cosh(W'_C/L_C)}{\sinh(W'_C/L_C)} (e^{V_{BC}/V_t} - 1)$$

$$I_{En} = qA \frac{D_B}{L_B} n_{B0} \left[\frac{\cosh(W/L_B)}{\sinh(W/L_B)} (e^{V_{BE}/V_t} - 1) - \frac{1}{\sinh(W/L_B)} (e^{V_{BC}/V_t} - 1) \right]$$

$$I_{Cn} = qA \frac{D_B}{L_B} n_{B0} \left[\frac{1}{\sinh(W/L_B)} (e^{V_{BE}/V_t} - 1) - \frac{\cosh(W/L_B)}{\sinh(W/L_B)} (e^{V_{BC}/V_t} - 1) \right]$$

Suppose that the BJT is biased such that $V_{BE} = 0.60$ V and $V_{BC} = 0$ V

- Calculate emitter injection efficiency γ , base transport factor α_T .
- Calculate the terminal currents I_E , I_C and I_B .

Hint:

- First calculate the built-in potential for each junction.
- Then obtain the widths of the quasi-neutral emitter, base and collector regions:
- Then determine the minority-carrier diffusivity and diffusion length for each of the quasi-neutral regions of the BJT, in order to calculate the various current components:
